

Form PTO-1449

INFORMATION DISCLOSURE CITATION
IN AN APPLICATION

(Use several sheets if necessary)

Docket Number 509982003300

Application Number 10/066,555

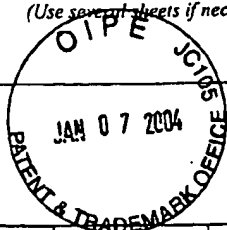
Applicant

Joerg Bischoff et al.

Filing Date January 31, 2002

Group Art Unit 2863

Mailing Date January 7, 2004



U.S. PATENT DOCUMENTS

Examiner Initials	Ref. No.	Date	Document No.	Name	Class	Subclass	Filing Date If Appropriate
kg	1.	6/1/1982	4,332,473	Ono			
	2.	5/29/1990	4,929,083	Brunner			
	3.	9/30/1997	5,672,520	Natsume			
	4.	9/13/1994	5,347,356	Ota et al.			
	5.	8/13/1996	5,545,593	Watkins et al.			
	6.	6/27/2000	6,079,256	Bareket			
	7.	4/22/1997	5,622,796	Canestrari et al.			
	8.	11/21/1995	5,468,580	Tanaka			
	9.	9/19/1995	5,452,090	Progler et al.			
	10.	5/7/2002	6,383,888	Stirton	430	22	
	11.	10/7/1997	5,674,650	Dirksen et al.	430	22	
	12.	9/24/2002	6,457,169	Ross	716	4	
	13.	12/3/2002	6,489,068	Kye	382	144	
	14.	8/18/1998	5,795,687	Yasuda	430	22	
kg	15.	10/31/2002	US 2002/0158193 A1 10/074561	Sezginer et al.	356	401	
kg	16.	1/2/2003	US 2003/0002043 A1	Abdulhalim et al.	356	400	

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IC 2800 MAIL ROOM

FOREIGN PATENT DOCUMENTS

Examiner Initials	Ref. No.	Date	Document No.	Country	Class	Subclass	Translation YES NO
kg	17.	9/7/1988	0 281 030 A2	EPO			
	18.	4/17/1991	0 422 395 A2	EPO			
	19.	1/18/1995	0 634 702 A1	EPO			
	20.	6/29/1988	0 272 853 A2	EPO			
kg	21.	3/28/2002	02/25723 A2	WO			

EXAMINER:

kgul

DATE CONSIDERED:

3/30/04

EXAMINER: Initial if citation considered, whether or not the citation conforms with MPEP 609. Draw a line through the citation if not in conformance and not considered. Include a copy of this form with next communication to applicant.

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	Applicant Joerg Bischoff et al.	
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22.	12/4/1997	97/45773	WO				
23.	12/14/2000	19925831 A1 with Abstract in English and English Translation	DE			X	

OTHER DOCUMENTS

(including author, title, Date, Pertinent Pages, Etc.)

Examiner Initials	Ref. No.	Title
kg	24.	Neal T. Sullivan, Semiconductor Pattern Overlay, 15 pages, Digital Equipment Corp., Advanced Semiconductor Development, Hudson, MA 01749-2895
kg	25.	Lifeng, Li "Symmetries of Cross-Polarization Diffraction Coefficients of Gratings." <i>J. Opt. Soc. Am. A</i> /Vol.17, No. 5 (2000).
kg	26.	Bischoff, J. et al. "Light Diffraction Based Overlay Measurement." <i>Proc. SPIE</i> Vol. 4344, pg. 222-233, <i>Metrology, Inspection, and Process Control for Microlithography XV</i> , (2001).

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EXAMINER: <i>kg</i>	DATE CONSIDERED: 3/30/04
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